Features

- Wide Power Supply Range, 3.0 V to 5.5 V
- Fast Read Access Time 120 ns
- Compatible with JEDEC Standard AT27C512R
- Low Power 3.3-Volt CMOS Operation
 20 μA max. Standby
 29 mW max. Active at 5 MHz for V_{CC} = 3.6 V
 110 mW max. Active at 5 MHz for V_{CC} = 5.5 V
- Wide Selection of JEDEC Standard Packages 28-Lead 600-mil PDIP and Cerdip 32-Pad PLCC and LCC 28-Lead TSOP and SOIC
- High Reliability CMOS Technology 2000 V ESD Protection 200 mA Latchup Immunity
- Rapid Programming 100 μs/byte (typical)
- Two-line Control
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

Description

The AT27LV512R chip is a low power, low voltage 524,288 bit ultraviolet erasable and electrically programmable read only memory (EPROM) organized as 64K x 8 bits. It requires only one supply in the range of 3.0 to 5.5 V in normal read mode operation, making it ideal for portable systems.

With a typical power draw of only 10 mW at 1 MHz and V_{CC} at 3.3 V, the AT27LV512R draws less than one-fifth the power of a standard 5-V EPROM. Standby mode supply current is typically less than 1 μ A at 3.3 V. (continued)

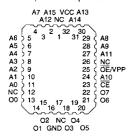
Pin Configurations

Pin Name	Function
A0-A15	Addresses
O0-O7	Outputs
CE	Chip Enable
OE /VPP	Output Enable
NC	No Connect

CDIP, PDIP, SOIC Top View

	$\overline{}$		1
A15 C	1	28	□ vcc
		27	□ A14
A7 🗆	3	26	□ A13
A6 □	2 3 4 5	25	□ A8 □
A5 🗆	5	24	□ A9
A4 🗆	6	25 24 23 22	□ A11
A3 🗆	7	22	Þ ŌĒ∕VPP
A2 🗆	8	21 20 19	□ A10
A1 🗆	9	20	Þ CE
A0 C	10	19	Þ 07
O0 🗆	11	18	P 06
01 🗆	12 13	17	D 05
O2 🗆	13	16	P 04
GND C	14	15	□ O3

LCC, PLCC Top View



TSOP Top View

Type 1

		. 71			
DEVPP A	22		21 00] <u>ce</u>	A10
A9 ^{A11} 5	23 24		19 20	Р	07
A13 A8	25 26		17	06	05
vccA14 B	27 28		15 16	₽ 04	03
A12 A15	1 2		13	GND	02
A6 A7 🗄	3 4		11	E 01	00
A4 A5	5 7		9 10	E AO	
^* a3 ₹_	7 6		9 8	_5 A2	AI

Note: PLCC Package Pins 1 and 17 are DON'T CONNECT.



512K (64K x 8) Low Voltage UV Erasable CMOS EPROM ž



Description (Continued)

The AT27LV512R comes in a choice of industry standard JEDEC-approved packages, including: one-time programmable (OTP) plastic PDIP, PLCC, SOIC, and TSOP, as well as windowed ceramic Cerdip and LCC. All devices feature two-line control ($\overline{\text{CE}}$, $\overline{\text{OE}}$) to give designers the flexibility to prevent bus contention.

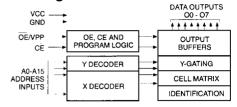
The AT27LV512R operating with V_{CC} at 3.0 V produces TTL level outputs that are compatible with standard TTL logic devices operating at $V_{CC} = 5.0 \text{ V}$.

Atmel's 27LV512R has additional features to ensure high quality and efficient production use. The Rapid Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100 μ s/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages. The AT27LV512R programs identically as an AT27C512R.

Erasure Characteristics

The entire memory array of the AT27LV512R is erased (all outputs read as VOH) after exposure to ultraviolet light at a wavelength of 2537 Å. Complete erasure is assured after a minimum of 20 minutes exposure using 12,000 µW/cm² intensity lamps spaced one inch away from the chip. Minimum erase time for lamps at other intensity ratings can be calculated from the minimum integrated erasure dose of 15 W-sec/cm². To prevent unintentional erasure, an opaque label is recommended to cover the clear window on any UV erasable EPROM which will be subjected to continuous fluorescent indoor lighting or sunlight.

Block Diagram



Absolute Maximum Ratings*

Temperature Under Bias40°C to +85°C
Storage Temperature65°C to +125°C
Voltage on Any Pin with Respect to Ground2.0 V to +7.0 V ⁽¹⁾
Voltage on A9 with Respect to Ground2.0 V to +14.0 V ⁽¹⁾
V _{PP} Supply Voltage with Respect to Ground2.0 V to +14.0 V ⁽¹⁾
Integrated UV Erase Dose7258 W•sec/cm ²

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Notes:

1. Minimum voltage is -0.6 V dc which may undershoot to -2.0 V for pulses of less than 20 ns. Maximum output pin voltage is $V_{\rm CC}$ + 0.75 V dc which may be exceeded if certain precautions are observed (consult application notes) and which may overshoot to +7.0 V for pulses of less than 20 ns.

Operating Modes

Mode \ Pin	CE	OE/V _{PP}	Ai	Vcc	Outputs
Read	VIL	VIL	Ai	Vcc	Douт
Output Disable	VIL	VIH	X ⁽¹⁾	Vcc	High Z
Standby	VIH	X	X	Vcc	High Z
Rapid Program ⁽²⁾	VIL	V _{PP}	Ai	Vcc (2)	DiN
PGM Verify ⁽²⁾	VIL	VIL	Ai	Vcc (2)	Dout
PGM Inhibit (2)	VIH	Vpp	Х	Vcc (2)	High Z
Product Identification ^{(2),(4)}	VIL	VIL	A9 = V _H ⁽³⁾ A0 = V _{IH} or V _{IL} A1-A15 = V _{IL}	Vcc (2)	Identification Code

Notes: 1. X can be V_{IL} or V_{IH}.

- Refer to Programming characteristics. Programming modes require V_{CC} > 4.5 V.
- 3. $V_H = 12.0 \pm 0.5 \text{ V}$.

4. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}) , except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.

3

D.C. and A.C. Operating Conditions for Read Operation

		AT27LV512R						
		-12	-15	-20	25			
Operating Temperature	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C	0°C - 70°C			
(Case)	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C			
Vcc Power Supply		3.0 V to 5.5 V						

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D.C. and Operating Characteristics for Read Operation

(VCC = 3.0 V to 5.5 V unless otherwise specified)

Symbol	Parameter	Condi	tion		Min	Max	Units
l _L ;	Input Load Current	VIN = C	V to Vcc			±1_	μА
ILO	Output Leakage Current	Vout =	= 0 V to Vcc			±5	μА
		l (C	MOCY CE Very ARM	Vcc =	3.6 V	20	μА
Isa	V _{CC} ⁽¹⁾ Standby Current	ISB1 (C	MOS), $\overline{CE} = V_{CC} \pm 0.3 \text{ V}$	Vcc =	5.5 V	100	μА
136	VCC Cianaby Current	/T	TI) OF 0040 V 05 V	Vcc =	3.6 V	100	μΑ
		ISB2 (I	ISB2 (TTL), $\overline{CE} = 2.0$ to Vcc + 0.5 V		5.5 V	1	mA
	Vcc Active Current	loc ₁	f = 5 MHz, lout = 0 mA,	Com.		8	mA
lcc			CE = VIL, VCC = 3.6 V	ind.		10	mA
100		ICC2 $\frac{f = 5 \text{ MHz, lout} = 0 \text{ mA}}{CE} = V_{IL}, V_{CC} = 5.5 \text{ V}$	f = 5 MHz, lout = 0 mA	Com.		20	mA
			Ind.		25	mA	
VIL	Input Low Voltage				-0.6	8.0	
VIH	Input High Voltage				2.0	V _{CC} +0.5	٧
Vai	Output Law Valtage	loL = 2	.0 mA			.4	٧
VoL	Output Low Voltage	lo _L = 1	00 μΑ			.2	٧
Vau	Outnut High Voltage	Іон = -	IOH = -2.0 mA		2.4	_	٧
Vон	Output High Voltage	Іон = -	100 μA		Vcc-0.2	2	V

Notes: 1. $V_{\rm CC}$ must be applied simultaneously or before $V_{\rm PP}$, and removed simultaneously or after $V_{\rm PP}$.

A.C. Characteristics for Read Operation (VCC = 3.0V to 5.5V)

							AT27L	V512	7			
	•				12	-1	15	-2	20	-2	25	
Symbol	Parameter	Condition		Min	Мах	Min	Max	Min	Max	Min	Max	Units
tacc (3)	(3) Address to Cutout Balan	CE = OE/VPP	Com.		120		150		200		250	ns
tacc (3) Address to Output Delay	Address to Odiput Delay	= VIL	Ind.		120		150		200		250	ns
tcE (2)	CE to Output Delay	OE/VPP = VIL			120		150		200		250	ns
toE (2,3)	OE/V _{PP} to Output Delay	CE = VIL			50		60		70		100	ns
t _{DF} ^(4,5)	OE/Vpp or CE High to Output Float				40		50		50		50	ns
tон	Output Hold from Address, CE or OE/Vpp, whichever occurred first		-	0		0		0		0		ns

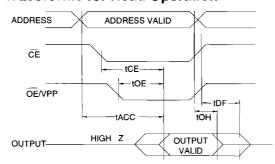
Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

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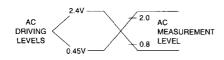
A.C. Waveforms for Read Operation (1)



Notes:

- Timing measurement references are 0.8 V and 2.0 V. Input AC driving levels are 0.45 V and 2.4 V. See Input Test Waveforms and Measurement Levels.
- OE/V_{PP} may be delayed up to t_{CE}-t_{OE} after the falling edge of CE without impact on t_{CE}.
- OE/Vpp may be delayed up to tACC-tOE after the address is valid without impact on tACC.
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

Input Test Waveforms and Measurement Levels



t_R, t_F < 20 ns (10% to 90%)

Output Test Load



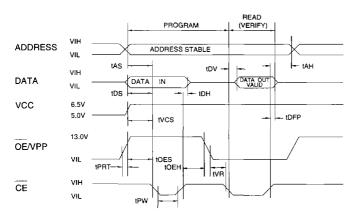
Note: C_L = 100 pF including jig capacitance.

Pin Capacitance $(f = 1 \text{ MHz}, T = 25^{\circ}\text{C})^{(1)}$

	Тур	Max	Units	Conditions
Cin	4	8	pF	$V_{IN} = 0 V$
Соит	8	12	pF	V _{OUT} = 0 V

Notes: 1. Typical values for 5-V supply voltage. This parameter is only sampled and is not 100% tested.

Programming Waveforms (1)



Notes:

- 1. The Input Timing Reference is 0.8 V for V_{IL} and 2.0 V for V_{IH} .
- 2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.

D.C. Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C$, $V_{CC} = 6.5 \pm 0.25 V$, $\overline{OE/V_{PP}} = 13.0 \pm 0.25 V$

Sym-		Test	Lir	nits	_
bol	Parameter	Conditions	Min	Max	Units
lu	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		10	μА
VIL	Input Low Level	(All Inputs)	-0.6	8.0	٧
ViH	Input High Level		2.0	V _{CC+} 1	٧
Vol	Output Low Volt.	I _{OL} = 2.1 mA		.45	V
Vон	Output High Volt.	lon = -400 μA	2.4		٧
lcc2	V _{CC} Supply Currer (Program and Ver			25	mA
IPP2	OE/VPP Current	CE = VIL		25	mA
ViD	A9 Product Identification Voltage		11.5	12.5	٧

A.C. Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C$, $V_{CC} = 6.5 \pm 0.25 \text{ V}$, $\overline{\text{OE}/V_{PP}} = 13.0 \pm 0.25 \text{ V}$

1A ≥ 25 ± 5 C, VCC = 0.5 ± 0.25 V, OE/VPP = 13.0 ± 0.25 V						
Sym- bol	Parameter	Test Conditions* (see Note 1)	Li r Min	nits Max l	Units	
tas	Address Setup Tim	е	2		μS	
toes	OE/V _{PP} Setup Time	9	2		μS	
toen	OE/V _{PP} Hold Time		2		μS	
tos	Data Setup Time		2		μS	
tan	Address Hold Time	,	0		μS	
tDH	Data Hold Time		2		μS	
tDFP	CE High to Out- put Float Delay	(Note 2)	0	130	ns	
tvcs	V _{CC} Setup Time		2		μS	
tpw	CE Program Pulse Width	(Note 3)	95	105	μS	
t _{DV}	Data Valid from CE	(Note 2)		1	μS	
tvR	OE/V _{PP} Recovery	Time	2		μS	
tPRT	OE/V _{PP} Pulse Rise Time During Progra		50		ns	

*A.C. Conditions of Test:

Input Rise and Fall Times (10% to 90%)	. 20 ns
Input Pulse Levels 0.45 V t	o 2.4 V
Input Timing Reference Level 0.8 V t	o 2.0 V
Output Timing Reference Level 0.8 V t	o 2 0 V

Notes:

- V_{CC} must be applied simultaneously or before OE/V_{PP} and removed simultaneously or after OE/V_{PP}.
- This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
- 3. Program Pulse width tolerance is 100 µsec±5%.

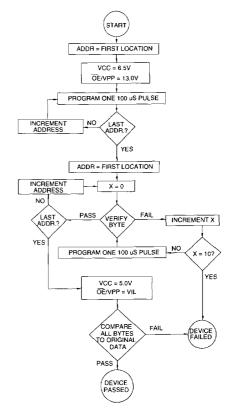
Atmel's 27LV512R Integrated Product Identification Code

	Pins						Hex			
Codes	A0	07	O 6	O 5	04	ОЗ	02	01	00	Data
Manufacturer	0	0	-	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	1	1	0	1	0D

Note: 1. The AT27LV512R has the same Product Identification Code as the AT27C512R. Both are programming compatible.

Rapid Programming Algorithm

A 100 μs \overline{CE} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5 V and \overline{OE}/V_{PP} is raised to 13.0 V. Each address is first programmed with one 100 μs \overline{CE} pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 μs pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. \overline{OE}/V_{PP} is then lowered to V_{IL} and V_{CC} to 5.0 V. All bytes are read again and compared with the original data to determine if the device passes or fails.







Ordering Information

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A	lcc (mA)		,	1		
tacc (ns)	Vcc :	= 3.6 V Standby	Ordering Code	Package	Operation Range	
120	8	0.02	AT27LV512R-12DC AT27LV512R-12JC AT27LV512R-12LC AT27LV512R-12PC AT27LV512R-12PC AT27LV512R-12TC	28DW6 32J 32LW 28P6 28R 28T	Commercial (0°C to 70°C)	
120	10	0.02	AT27LV512R-12DI AT27LV512R-12JI AT27LV512R-12LI AT27LV512R-12PI AT27LV512R-12PI AT27LV512R-12RI AT27LV512R-12TI	28DW6 32J 32LW 28P6 28R 28T	Industrial (-40°C to 85°C)	
150	8	0.02	AT27LV512R-15DC AT27LV512R-15JC AT27LV512R-15LC AT27LV512R-15PC AT27LV512R-15PC AT27LV512R-15TC	28DW6 32J 32LW 28P6 28R 28T	Commercial (0°C to 70°C)	
150	10	0.02	AT27LV512R-15DI AT27LV512R-15JI AT27LV512R-15LI AT27LV512R-15PI AT27LV512R-15RI AT27LV512R-15TI	28DW6 32J 32LW 28P6 28R 28T	Industrial (-40°C to 85°C)	
200	8	0.02	AT27LV512R-20DC AT27LV512R-20JC AT27LV512R-20LC AT27LV512R-20PC AT27LV512R-20RC AT27LV512R-20TC	28DW6 32J 32LW 28P6 28R 28T	Commercial (0°C to 70°C)	
200	10	0.02	AT27LV512R-20DI AT27LV512R-20JI AT27LV512R-20LI AT27LV512R-20PI AT27LV512R-20RI AT27LV512R-20TI	28DW6 32J 32LW 28P6 28R 28T	Industrial (-40°C to 85°C)	
250	8	0.02	AT27LV512R-25DC AT27LV512R-25JC AT27LV512R-25LC AT27LV512R-25PC AT27LV512R-25RC AT27LV512R-25TC	28DW6 32J 32LW 28P6 28R 28T	Commercial (0°C to 70°C)	
250	10	0.02	AT27LV512R-25DI AT27LV512R-25JI AT27LV512R-25LI AT27LV512R-25PI AT27LV512R-25RI AT27LV512R-25TI	28DW6 32J 32LW 28P6 28R 28T	Industrial (-40°C to 85°C)	

Ordering Information

	Package Type				
28DW6	28 Lead, 0.600" Wide, Windowed, Ceramic Dual Inline Package (Cerdip)				
32J	32 Lead, Plastic J-Leaded Chip Carrier OTP (PLCC)				
32LW	32 Pad, Windowed, Ceramic Leadless Chip Carrier (LCC)				
28P6	28 Lead, 0.600" Wide, Plastic Dual Inline Package OTP (PDIP)	•			
28R	28 Lead, 0.330" Wide, Plastic Gull Wing Small Outline OTP (SOIC)				
28T	28 Lead, Plastic Thin Small Outline Package OTP (TSOP)				

